

April 1988 Revised April 1999

# 74F245

# **Octal Bidirectional Transceiver with 3-STATE Outputs**

## **General Description**

The 74F245 contains eight non-inverting bidirectional buffers with 3-STATE outputs and is intended for bus-oriented applications. Current sinking capability is 24 mA at the A Ports and 64 mA at the B Ports. The Transmit/Receive (T/R) input determines the direction of data flow through the bidirectional transceiver. Transmit (active HIGH) enables data from A Ports to B Ports; Receive (active LOW) enables data from B Ports to A Ports. The Output

Enable input, when HIGH, disables both A and B Ports by placing them in a High Z condition.

### **Features**

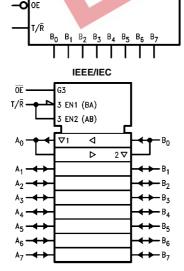
- Non-inverting buffers
- Bidirectional data path
- A outputs sink 24 mA
- B outputs sink 64 mA

## **Ordering Code:**

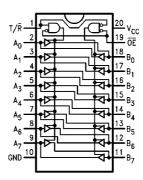
		400 7.20%
Order Number	Package Number	Package Description
74F245SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F245SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F245MSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74F245MTC	MTC20	20-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide
74F245PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

## **Logic Symbols**



## **Connection Diagram**



# **Unit Loading/Fan Out**

Din Names	Description	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>		
Pin Names	Description	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>		
ŌĒ	Output Enable Input (Active LOW)	1.0/2.0	20 μA/–1.2 mA		
T/R	Transmit/Receive Input	1.0/2.0	20 μA/–1.2 mA		
A <sub>0</sub> -A <sub>7</sub>	Side A Inputs or	3.5/1.083	70 μA/–0.65 mA		
	3-STATE Outputs	150/40(38.3)	-3 mA/24 mA (20 mA)		
B <sub>0</sub> -B <sub>7</sub>	Side B Inputs or	3.5/1.083	70 μA/–0.65 mA		
	3-STATE Outputs	600/106.6(80)	-12 mA/64 mA (48 mA)		

## **Truth Table**

	Input	s	Output		
	OE	T/R	Output		
	L	L	Bus B Data to Bus A		
	L	Н	Bus A Data to Bus B		
	Н	X	High Z State		
e Leve			.com		

H = HIGH Voltage Level

L = LOW Voltage Level X = Immaterial

## **Absolute Maximum Ratings**(Note 1)

## **Recommended Operating Conditions**

Storage Temperature -65°C to +150°C

Ambient Temperature under Bias -55°C to +125°C Junction Temperature under Bias -55°C to +150°C V<sub>CC</sub> Pin Potential to Ground Pin -0.5V to +7.0V

Input Voltage (Note 2) -0.5V to +7.0VInput Current (Note 2) -30 mA to +5.0 mA

Voltage Applied to Output in HIGH State (with  $V_{CC} = 0V$ )

Standard Output –0.5V to  $V_{\mbox{\footnotesize CC}}$ 3-STATE Output -0.5V to +5.5V

Current Applied to Output

twice the rated  $I_{OL}$  (mA) in LOW State (Max) ESD Last Passing Voltage (Min)

Free Air Ambient Temperature 0°C to +70°C Supply Voltage +4.5V to +5.5V

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

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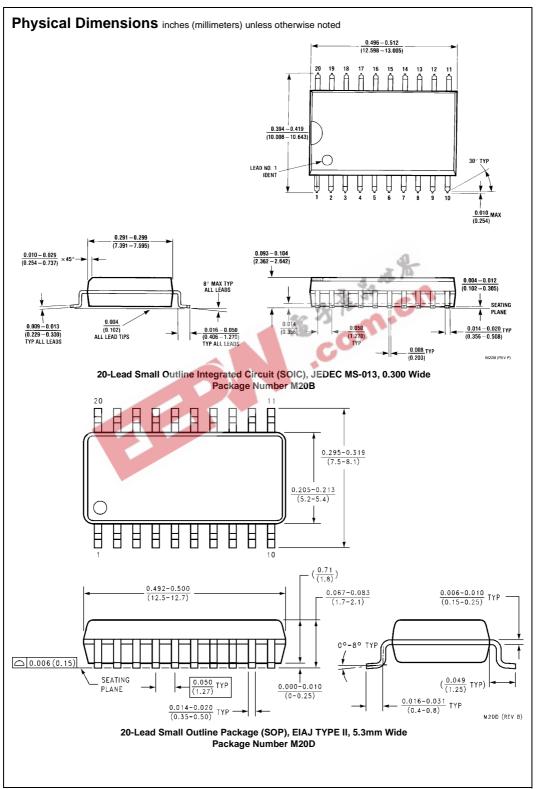
Note 2: Either voltage limit or current limit is sufficient to protect inputs.

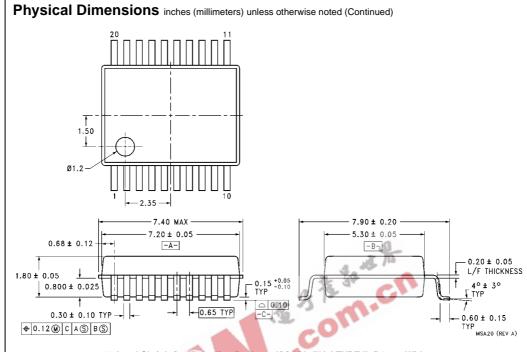
## **DC Electrical Characteristics**

Symbol	Parameter	Min	Тур	Max	Units	Vcc	Conditions
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal
V <sub>IL</sub>	Input LOW Voltage			0.8	V	C	Recognized as a LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage 10% V <sub>CC</sub>	2.4		CIL	V	Min	$I_{OH} = -3 \text{ mA } (A_n)$
	10% V <sub>CC</sub>	2.0		-	0		$I_{OH} = -15 \text{ mA } (B_n)$
	5% V <sub>CC</sub>	2.7					$I_{OH} = -3 \text{ mA } (A_n)$
V <sub>OL</sub>	Output LOW Voltage 10% V <sub>CC</sub>	77. 1		0.5	V	Min	$I_{OL} = 24 \text{ mA } (A_n)$
	10% V <sub>CC</sub>			0.55			$I_{OL} = 64 \text{ mA } (B_n)$
I <sub>IH</sub>	Input HIGH Current			5.0	μΑ	Max	V <sub>IN</sub> = 2.7V
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7.0	μΑ	Max	$V_{IN} = 7.0V (\overline{OE}, T/\overline{R})$
I <sub>BVIT</sub>	Input HIGH Current Breakdown (I/O)			0.5	mA	Max	$V_{IN} = 5.5 \text{ V } (A_n, B_n)$
I <sub>CEX</sub>	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC} (A_n, B_n)$
V <sub>ID</sub>	Input Leakage	4.75			V	0.0	$I_{ID} = 1.9 \mu A$
	Test						All Other Pins Grounded
I <sub>OD</sub>	Output Leakage			3.75	μΑ	0.0	V <sub>IOD</sub> = 150 mV
	Circuit Current						All Other Pins Grounded
I <sub>IL</sub>	Input LOW Current			-1.2	mA	Max	$V_{IN} = 0.5V (T/\overline{R}, \overline{OE})$
I <sub>IH</sub> + I <sub>OZH</sub>	Output Leakage Current			70	μΑ	Max	$V_{OUT} = 2.7V (A_n, B_n)$
I <sub>IL</sub> + I <sub>OZL</sub>	Output Leakage Current			-650	μΑ	Max	$V_{OUT} = 0.5V (A_n, B_n)$
Ios	Output Short-Circuit Current	-60		-150	mA	Max	$V_{OUT} = 0V (A_n)$
		-100		-225			$V_{OUT} = 0V (B_n)$
I <sub>ZZ</sub>	Bus Drainage Test			500	μΑ	0.0V	$V_{OUT} = 5.25V(A_n, B_n)$
I <sub>CCH</sub>	Power Supply Current		70	90	mA	Max	V <sub>O</sub> = HIGH
I <sub>CCL</sub>	Power Supply Current		95	120	mA	Max	$V_O = LOW$
I <sub>CCZ</sub>	Power Supply Current		85	110	mA	Max	V <sub>O</sub> = HIGH Z

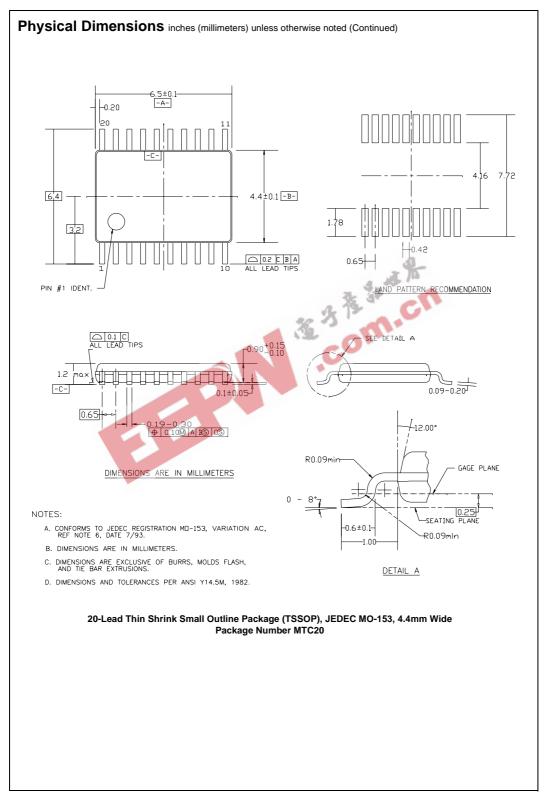
Symbol			$T_A = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$T_A = -55$ °C to +125°C $C_L = 50 \text{ pF}$		$T_A = 0$ °C to $+70$ °C $C_L = 50$ pF	
	Parameter								
		Min	Тур	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	2.5	4.2	6.0	2.0	7.5	2.0	7.0	n
t <sub>PHL</sub>	$A_n$ to $B_n$ or $B_n$ to $A_n$	2.5	4.2	6.0	2.0	7.5	2.0	7.0	
t <sub>PZH</sub>	Output Enable Time	3.0	5.3	7.0	2.5	9.0	2.5	8.0	
$t_{PZL}$		3.5	6.0	8.0	3.0	10.0	3.0	9.0	n
t <sub>PHZ</sub>	Output Disable Time	2.0	5.0	6.5	2.0	9.0	2.0	7.5	1
$t_{PLZ}$		2.0	5.0	6.5	2.0	10.0	2.0	7.5	

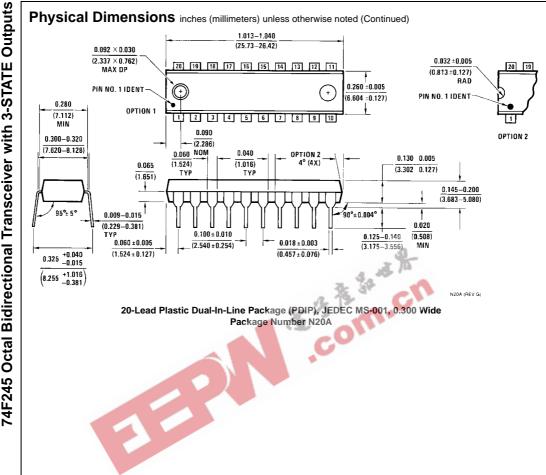






20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide Package Number MSA20





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